

### MOCVD Growth of InAlN/GaN Heterostructures on Si Substrate for UV Photodiode Application

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In<sub>x</sub>Al<sub>1-x</sub>N alloys with 17-18% indium composition are becoming popular in research due to their natural wide bandgap (i.e., 0.6 to 6.2 eV) and lattice matching GaN [1, 2]. In<sub>x</sub>Al<sub>1-x</sub>N alloys are very attractive for high electron mobility transistors (HEMTs), light emitting diodes (LEDs), solar cells and ultraviolet photodiodes (UVPD) applications [3-9] due to a wide spectrum of wavelength available by using ternary alloys. Besides, the In<sub>x</sub>Al<sub>1-x</sub>N-based devices can operate at high temperatures and have a long lifetime. Recently, In<sub>x</sub>Al<sub>1-x</sub>N has been widely studied and applied to various semiconductor devices. However, most reported research used sapphire substrate for growing In<sub>x</sub>Al<sub>1-x</sub>N alloys. A few studies used Si substrate due to the challenges of growing In<sub>x</sub>Al<sub>1-x</sub>N film on Si substrate, which exhibits an obvious lattice mismatch. High quality GaN buffer is one effective method used to obtain a high quality In<sub>x</sub>Ga<sub>1-x</sub>N [10], and in this study, it will be continuously used to improve the In<sub>x</sub>Al<sub>1-x</sub>N film on Si substrate using metal organic chemical vapor deposition (MOCVD) reactor.

In this study, we report on the growth of high quality In<sub>x</sub>Al<sub>1-x</sub>N/GaN heterostructures on Si substrate by MOCVD with various indium compositions. The lattice-matched In<sub>0.176</sub>Al<sub>0.838</sub>N/GaN structure shows a smooth surface with good crystalline quality. In addition, the ultraviolet photodiode device fabricated based on this structure shows excellent device characteristics with a low leakage current of 0.12 μA, and a high spectral response. It has good quantum efficiency of 94 mA/W and 44% at 265 nm.

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